

U.S. Particle Accelerator School
 Education in Beam Physics and Accelerator Technology

Simulations of Beam and Plasma Systems
 Steven M. Lund, David Bruhwiler, Rémi Lehe, Jean-Luc Vay and Daniel Winklehner
 Sponsoring University: Old Dominion University
 Hampton, Virginia – January 15-26, 2018

Mesh Refinement in Field Solvers

Jean-Luc Vay
 Lawrence Berkeley National Laboratory

This material is based upon work supported by the U.S. Department of Energy, Office of Science and the National Nuclear Security Administration, under Award Number(s) DE-AC02-05CH11231 and 17-SC-20-SC. Used resources of the National Energy Research Scientific Computing Center.

Outline

- Why mesh refinement?
- Potential issues
- Electrostatic mesh refinement
 - spurious self-force example
 - spurious self-force mitigation
 - application to the modeling of HCX injector
- Electromagnetic mesh refinement
 - spurious reflection of waves
 - spurious reflection of waves mitigation
 - Application to the modeling beam-induced plasma wake
- Special mesh refinement for particle emission
- Summary

Why mesh refinement?

To resolve density spikes & gradients.

Injector

emitter
Beam edge

Electron cloud

Electron density spikes

Plasma accelerator

Small electron beams

Coupling of AMR to PIC: issues

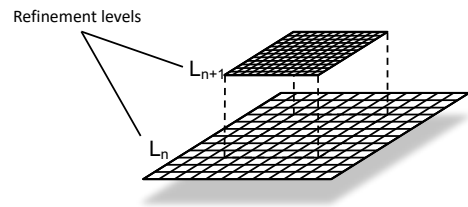
Mesh refinement implies:

- jump of resolution at coarse-fine interface,
- some procedure for coupling the solutions at the interface.

Consequences:

- loss of symmetry: self-force,
- loss of conservation laws,
- EM: waves reflection.

Electrostatic mesh refinement

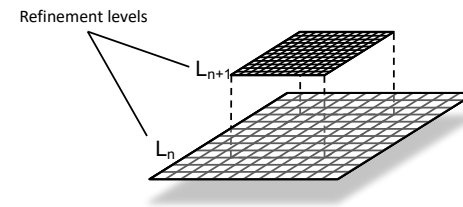


Solution to Poisson is a boundary value problem.
We can define the following simple procedure:

1. solve on coarse grid,
2. interpolate on fine grid boundaries,
3. solve on fine grid.



Electrostatic mesh refinement

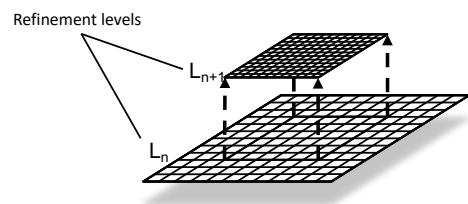


Solution to Poisson is a boundary value problem.
We can define the following simple procedure:

1. **solve on coarse grid,**
2. interpolate on fine grid boundaries,
3. solve on fine grid.



Electrostatic mesh refinement

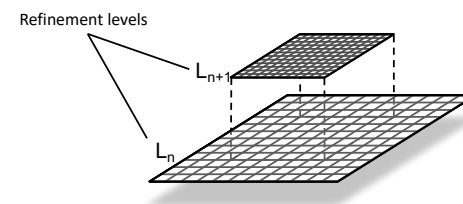


Solution to Poisson is a boundary value problem.
We can define the following simple procedure:

1. solve on coarse grid,
2. **interpolate on fine grid boundaries,**
3. solve on fine grid.



Electrostatic mesh refinement



Solution to Poisson is a boundary value problem.
We can define the following simple procedure:

1. solve on coarse grid,
2. interpolate on fine grid boundaries,
3. **solve on fine grid.**



Illustration potential problem: spurious self-force

Test using script test1partin1patch.py:

- Run with $l_{mr}=0$.

One charged macroparticle in a box with metallic BC

centered

not centered




Illustration potential problem: spurious self-force

Test using script test1partin1patch.py:

- Run with $l_{mr}=0$.

The macroparticle is attracted by its image from the closest metallic wall.




Illustration potential problem: spurious self-force

Test using script test1partin1patch.py:

- Run with $l_{mr}=0$.

We apply specular reflection at the boundary.




Illustration potential problem: spurious self-force

Test using script test1partin1patch.py:

- Run with $l_{mr}=0$.

The particle moves up and down.

Timestep	Physical solution (Position)	No refinement (Position)
0	30	30
100	25	25
200	0	0
300	25	25
400	30	30
500	30	30


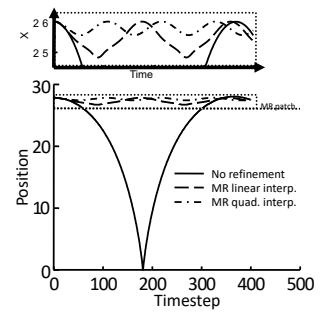
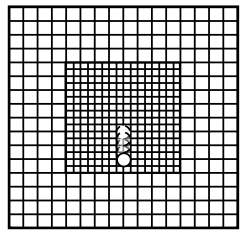


Illustration potential problem: spurious self-force

Test using script `test1partin1patch.py`:
 • Run with `l_mr=1`.

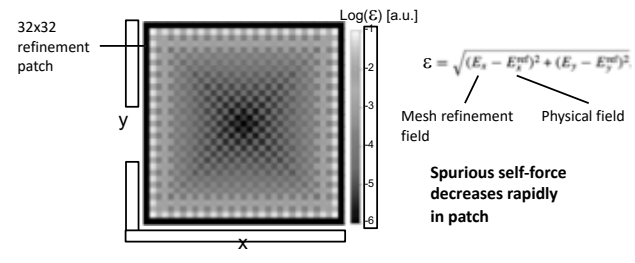
Now add a refinement patch.

→ Particle is trapped in patch by "spurious self-force"



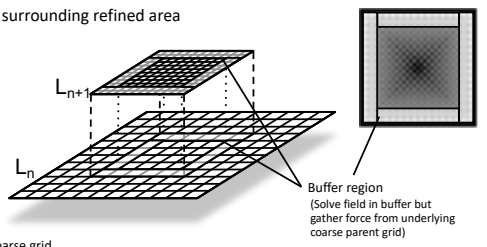
Spurious self-force: magnitude map

Map of spurious self-force as a function of particle position in refinement patch



Spurious self-force: mitigation

Add buffer region surrounding refined area

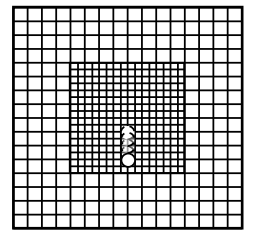


- 1 – solve on coarse grid,
 - 2 – interpolate on fine grid boundaries,
 - 3 – solve on fine grid,
 - 4 – disregard fine grid solution close to edge when gathering force onto particles.
- Thickness of buffer region provides user control of relative magnitude of spurious force.

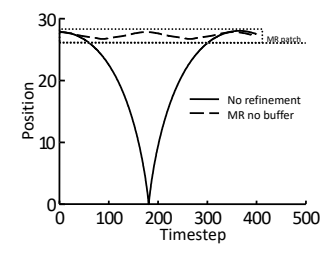
Spurious self-force: mitigation

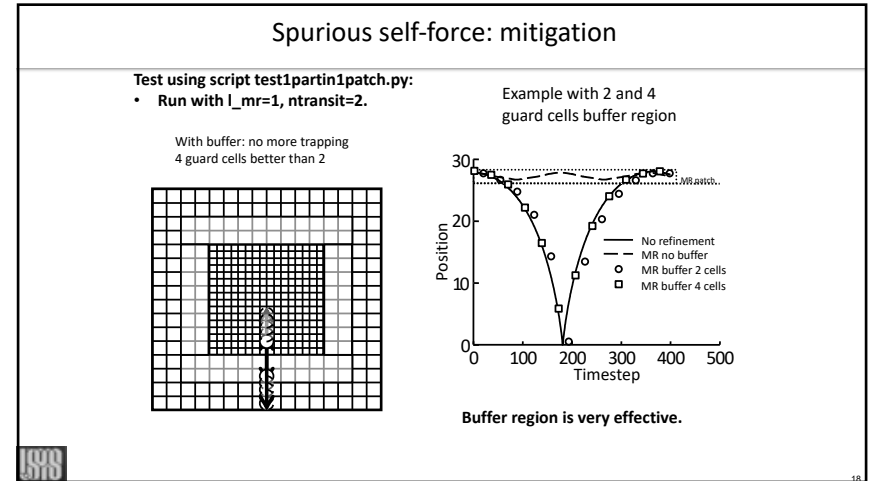
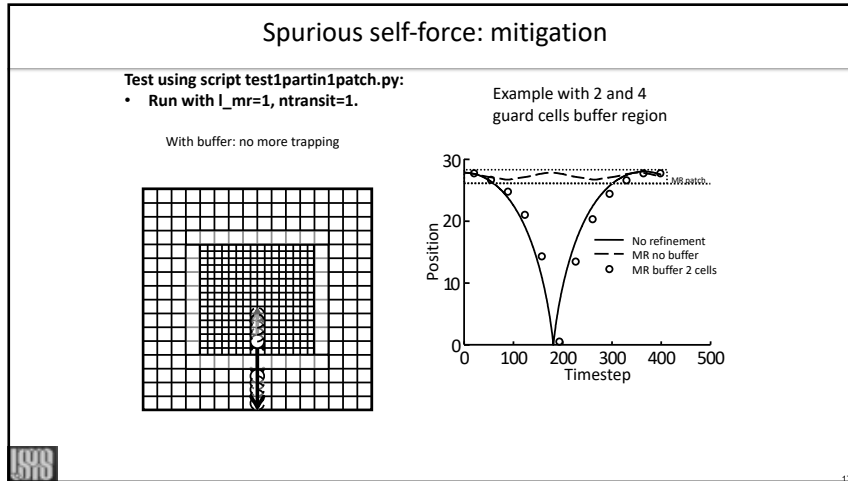
Test using script `test1partin1patch.py`:
 • Run with `l_mr=1, ntransit=0`.

No buffer: particle trapped in patch.



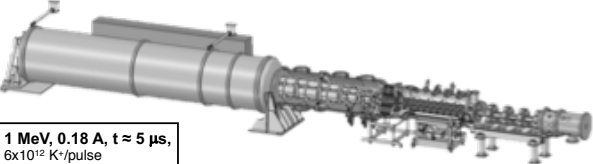
Example with 2 and 4 guard cells buffer region





Electrostatic AMR PIC example: HCX

High Current Experiment
(High Brightness Beam Transport Campaign, 2005)



**1 MeV, 0.18 A, $t \approx 5 \mu s$,
 6×10^{12} K⁻/pulse**

Heavy Ion Fusion program, LBNL

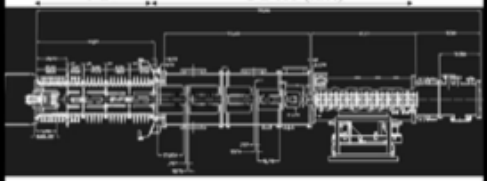
The Heavy Ion Fusion Virtual National Laboratory

USPS

Electrostatic AMR PIC example: HCX

WARP simulation of HCX

3-D 2-D XY (slice)

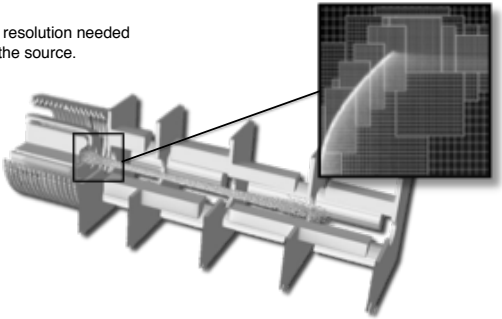


The Heavy Ion Fusion Virtual National Laboratory


USPS

Electrostatic AMR PIC example: HCX

Very high resolution needed to model the source.

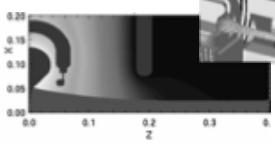


Source region is axisymmetric and is well captured with RZ simulations.


21

Modeling of source critical - determines initial shape of beam.

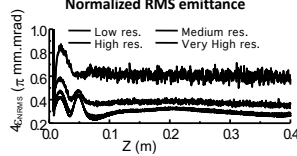
Axisymmetric (RZ) time-dependent simulations.



Run	Grid size	Nb particles
Low res.	56x640	~1M
Medium res.	112x1280	~4M
High res.	224x2560	~16M
Very High res.	448x5120	~64M

A fairly high resolution is needed to reach convergence


Normalized RMS emittance



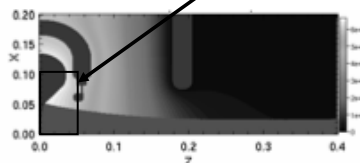
4 π ϵ_{rms} (mm.mrad)

Z (m)

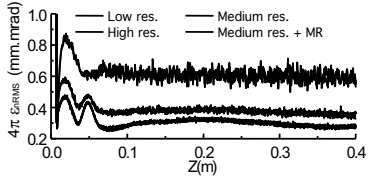
— Low res. — Medium res.
— High res. — Very High res.


22

First MR attempt - 1 MR block surrounding emitter.




Refining the emitter area is enough to recover emittance from converged high-resolution case.



Run	Grid size	Nb particles
Low res.	56x640	~1M
Medium res.	112x1280	~4M
High res.	224x2560	~16M
Medium res. + MR	112x1280	~4M

4 π ϵ_{rms} (mm.mrad)

Z(m)


23

First MR attempt - 1 MR block surrounding emitter (2).

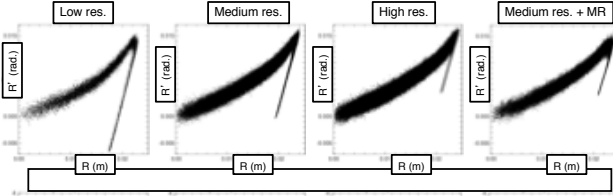
However, it is not enough for recovering details of distribution.

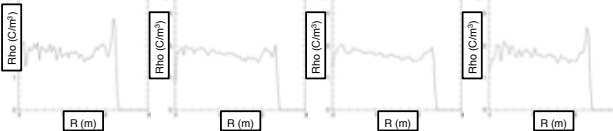
Low res.

Medium res.


High res.

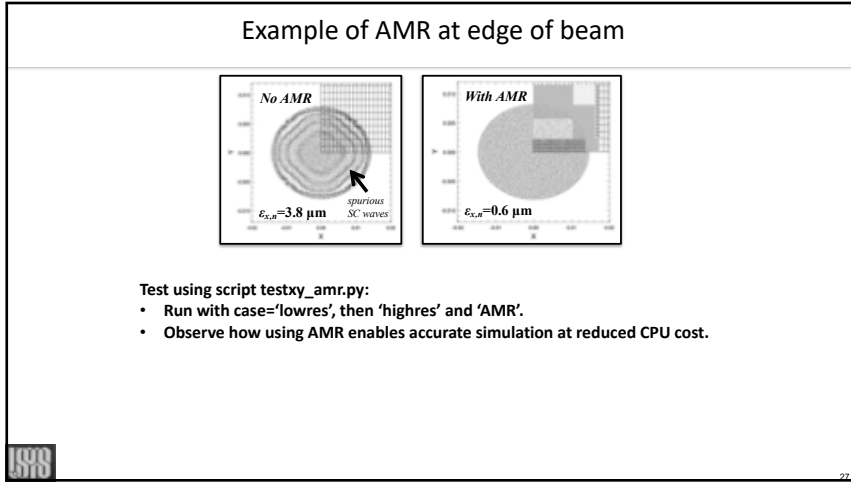
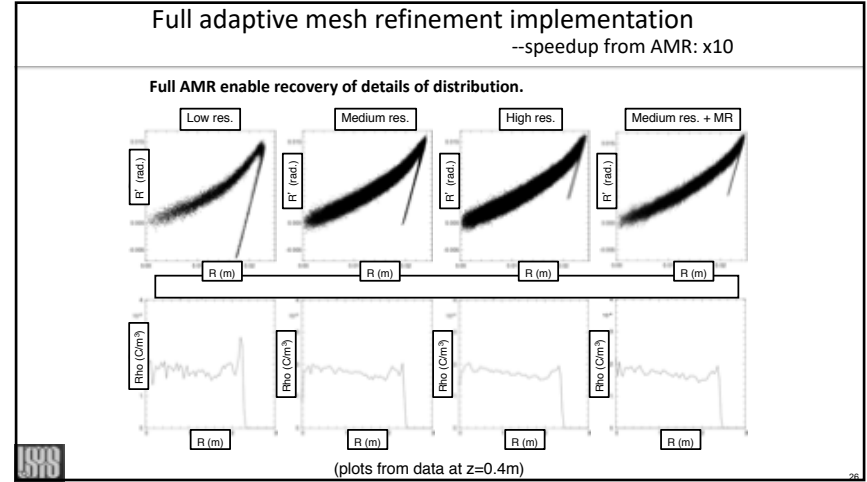
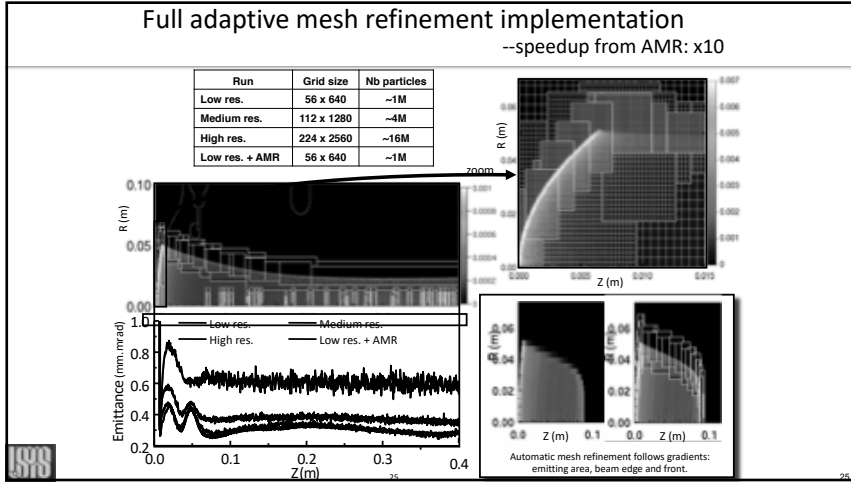
Medium res. + MR





(plots from data at z=0.4m)


24



- ### Summary of electrostatic AMR-PIC
- Simple method for electrostatic AMR-PIC was presented.
 - Buffer region mitigates spurious self-force effect very effectively.
 - Speedups of x10 demonstrated on simulation of injector.
 - Alternate methods such as multipole expansions have other advantages & drawbacks.

Outline

- Why mesh refinement?
- Potential issues
- Electrostatic mesh refinement
 - spurious self-force example
 - spurious self-force mitigation
 - application to the modeling of HCX injector
- Electromagnetic mesh refinement
 - spurious reflection of waves
 - spurious reflection of waves mitigation
 - Application to the modeling beam-induced plasma wake
- Special mesh refinement for particle emission
- Summary

1-D FDTD EM wave equation

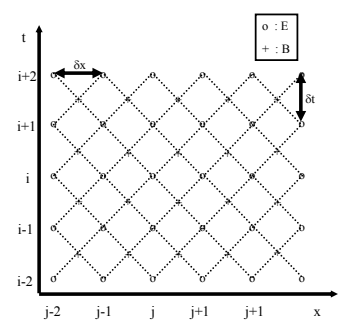
- We consider 1d wave equation (natural units)

$$\frac{\partial E}{\partial t} = \frac{\partial B}{\partial x}; \quad \frac{\partial B}{\partial t} = -\frac{\partial E}{\partial x}$$

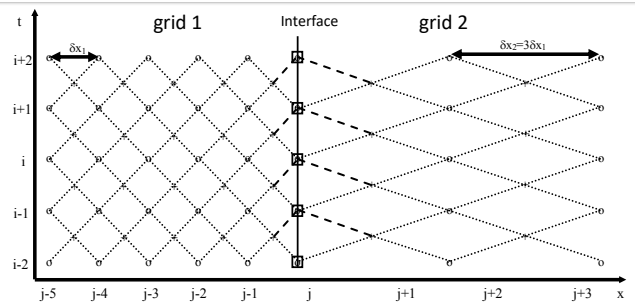
- staggered on a regular space time grid using finite-difference time-domain (FDTD) centered scheme

$$\frac{E_j^{i+1} - E_j^i}{\Delta t} = \frac{B_{j+1/2}^{i+1/2} - B_{j-1/2}^{i+1/2}}{\Delta x}$$

$$\frac{B_{j+1/2}^{i+1/2} - B_{j+1/2}^{i-1/2}}{\Delta t} = -\frac{E_{j+1}^i - E_{j-1}^i}{\Delta x}$$



1-D MR-EM: space refinement uncentered finite-difference



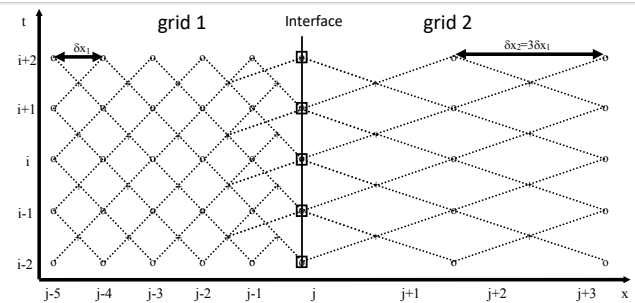
○ : finite-difference at positions ≠ j
 □ : finite-volume (=uncentered FD) at j

$$\frac{E_j^{i+1} - E_j^i}{\Delta t} = 2 \frac{B_{j+1/2}^{i+1/2} - B_{j-1/2}^{i+1/2}}{\Delta x_1 + \Delta x_2} \quad (\text{method 1})$$

or

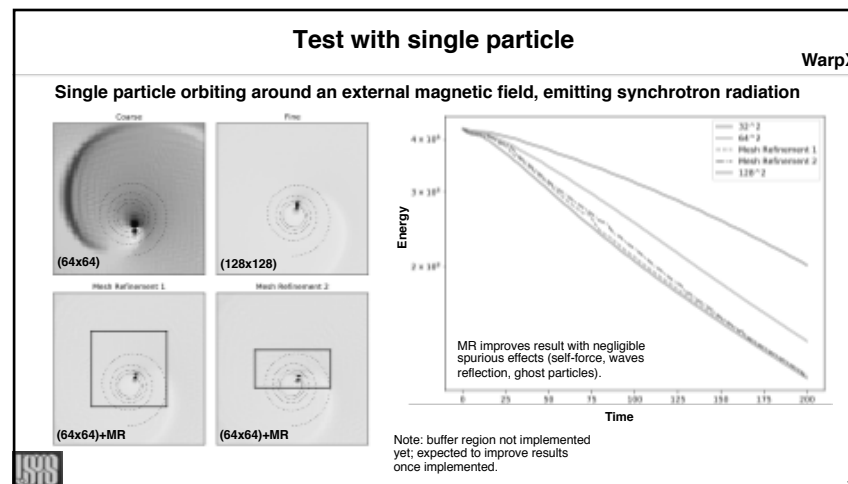
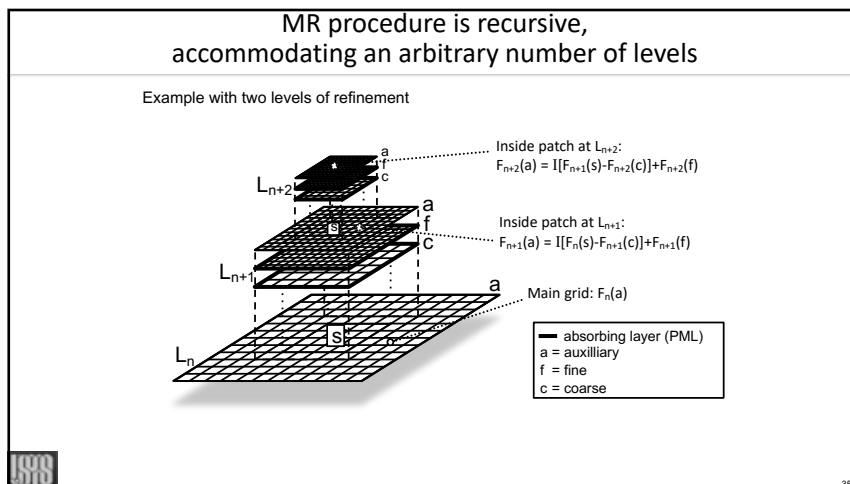
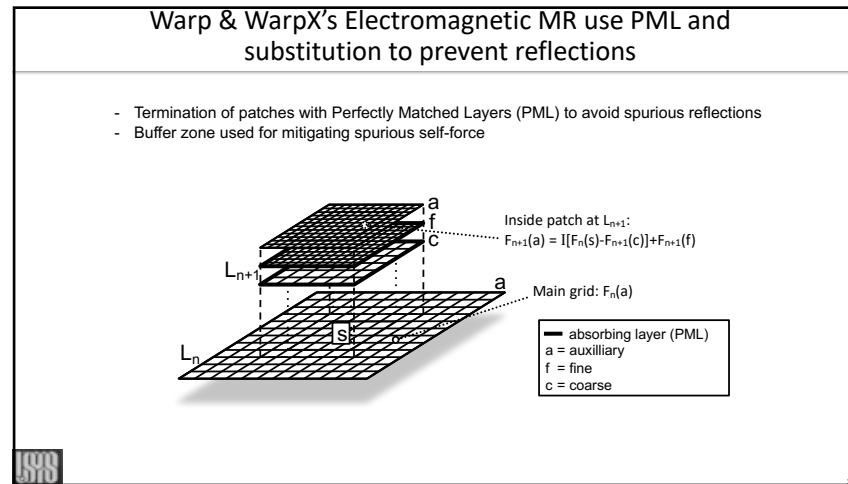
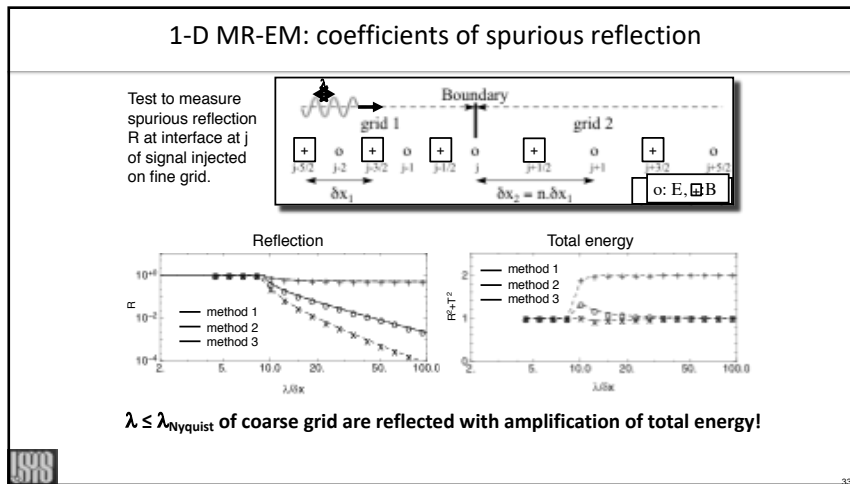
$$\frac{E_j^{i+1} - E_j^i}{\Delta t} = \frac{B_{j+1/2}^{i+1/2} - B_{j-1/2}^{i+1/2}}{\Delta x_2} \quad (\text{method 2})$$

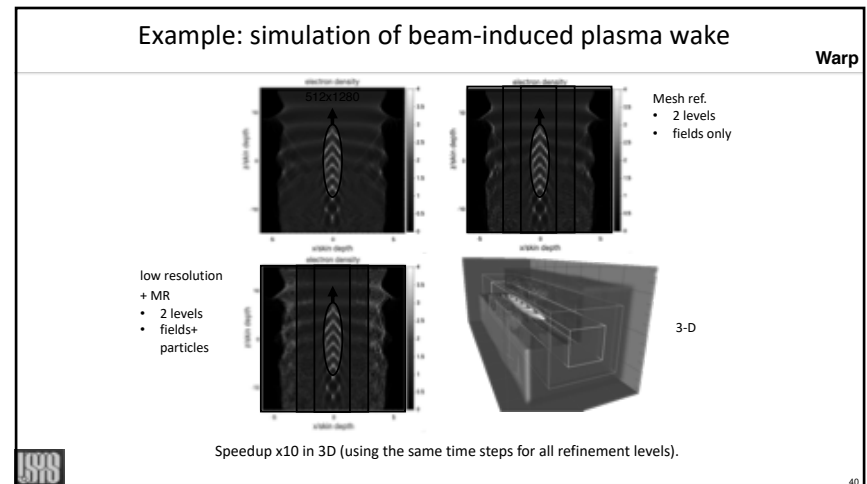
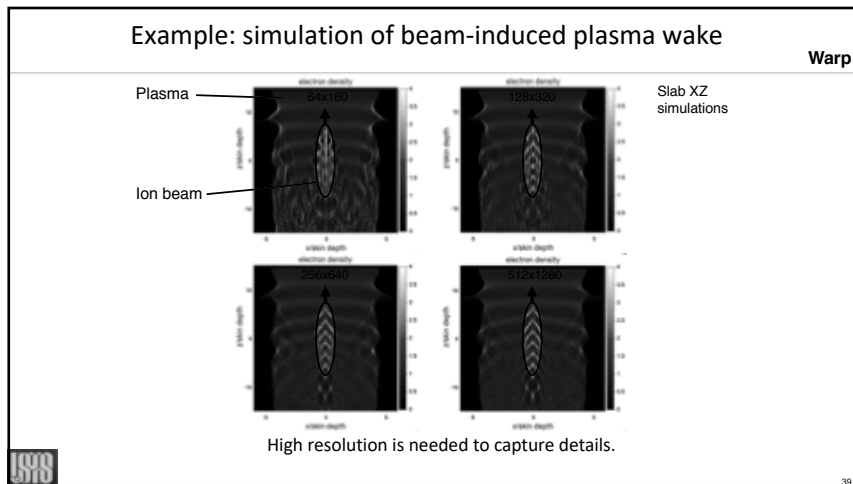
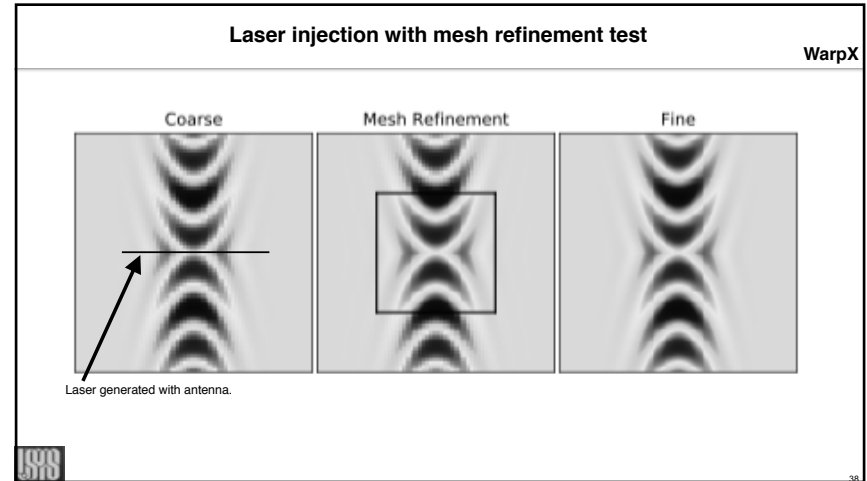
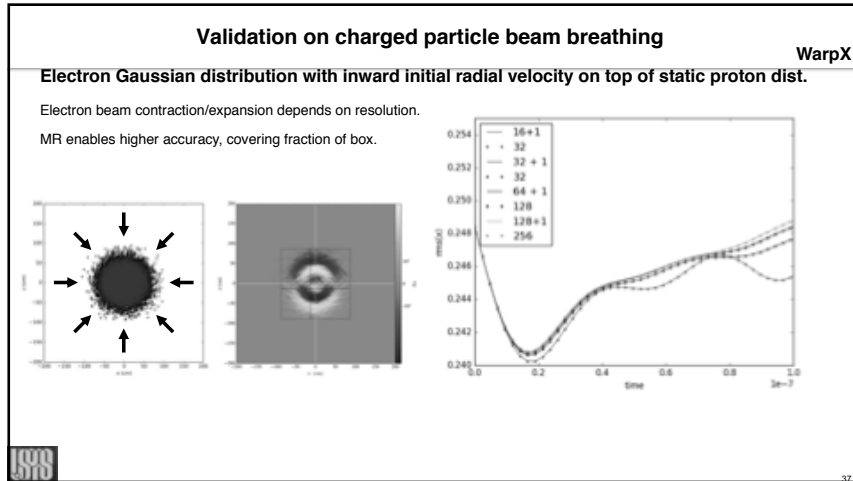
1-D MR-EM: space refinement centered finite-difference

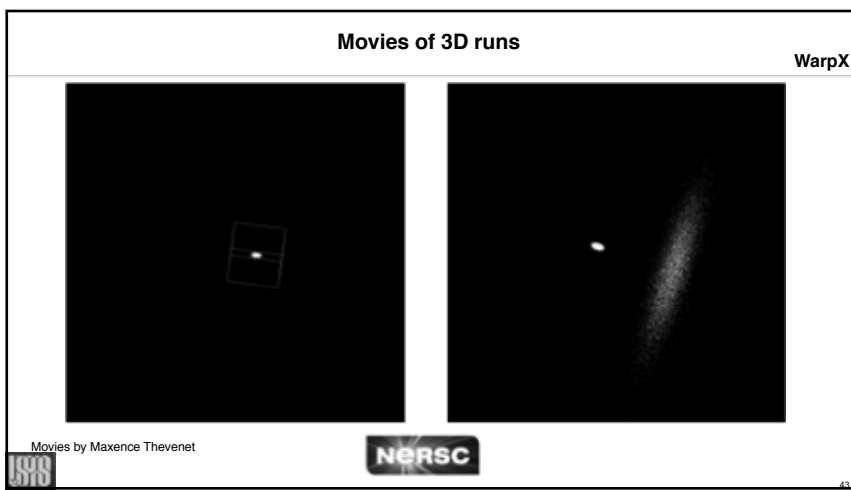
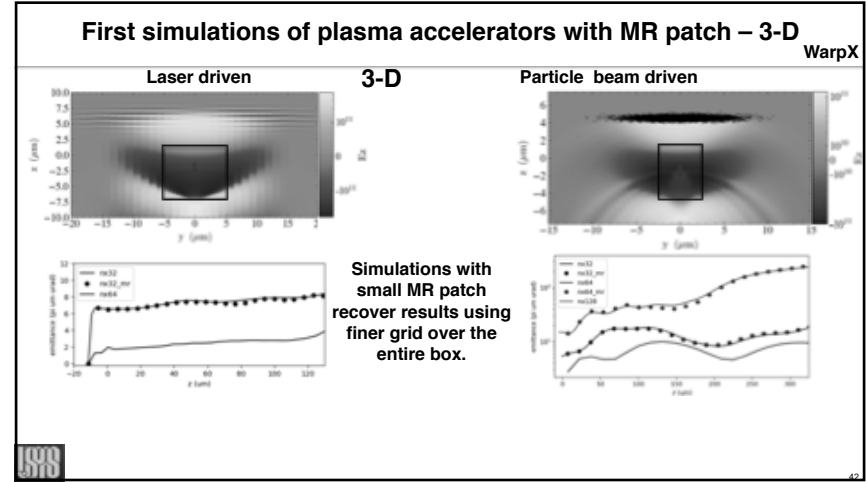
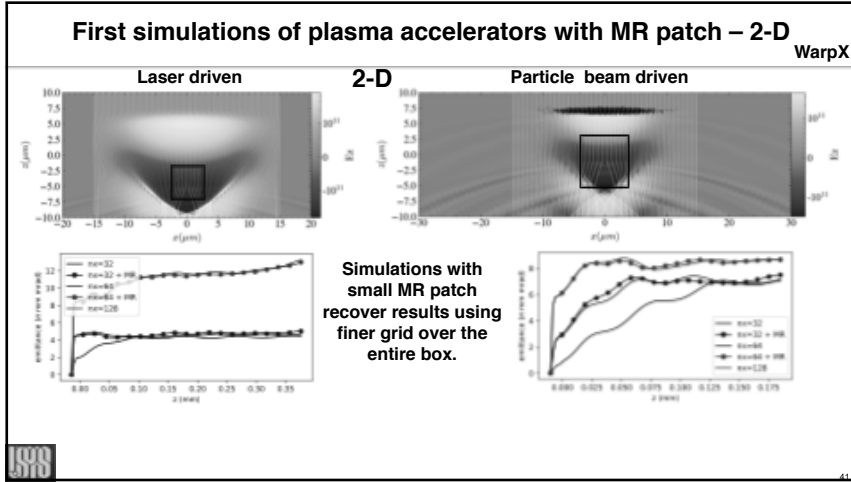


○ : finite-difference at positions ≠ j
 □ : 'jump' inside fine grid at j

$$\frac{E_j^{i+1} - E_j^i}{\Delta t} = \frac{B_{j+1/2}^{i+1/2} - B_{j-1/2}^{i+1/2}}{\Delta x_1} \quad (\text{method 3})$$







- ### Outline
- Why mesh refinement?
 - Potential issues
 - Electrostatic mesh refinement
 - spurious self-force example
 - spurious self-force mitigation
 - application to the modeling of HCX injector
 - Electromagnetic mesh refinement
 - spurious reflection of waves
 - spurious reflection of waves mitigation
 - Application to the modeling beam-induced plasma wake
 - Special mesh refinement for particle emission
 - Summary
-
-

3-D WARP simulation of HCX showed beam head scrapping

Rise-time $\tau = 800$ ns
beam head particle loss $< 0.1\%$

Rise-time $\tau = 400$ ns
zero beam head particle loss

- Head cleaner with shorter voltage rise-time.
- Questions:
 - what is the optimal rise-time?
 - can we produce and model very-fast rise-time?

Test: 1-D time-dependent modelling of Ion diode

Emitter Collector

V $V=0$

d

Applied voltage for Heaviside current history?

current time

Analytic solution from Lampel-Tiefenback

$$V(t) = \frac{t}{3\tau} \left[4 - \left(\frac{t}{\tau} \right)^2 \right] V_{max}$$

(τ : transit time)

Child-Langmuir

Front at time t

Test: 1D time-dependent modelling of Ion diode (algo 1)

Injection algorithm

Emitter d_i Collector

virtual surface

Child-Langmuir solution* + voltage drop between emitter and virtual surface determines current to inject.

$$I = \chi \frac{(V - V_s)^{3/2}}{d_i^2}; \chi = \frac{4}{9} \epsilon_0 \sqrt{\frac{2q}{m}}$$

$$\Rightarrow \Delta Q = Nq = I\Delta t$$

Result

Lampel-Tiefenback waveform

Simulation result exhibits large unphysical oscillation.

$N = 160$
 $\Delta t = 1$ ns
 $d = 0.4$ m

*1-D; $\Rightarrow J=I$ ($J=I/S, S=1$)

Unphysical oscillation related to Nb particles Injected/time step (N)

I (A)

Time (s)

— Analytic
— Simulation

$N = 160$
 $\Delta t = 1$ ns
 $d = 0.4$ m

Nb injected particles

Time steps

Ideally,

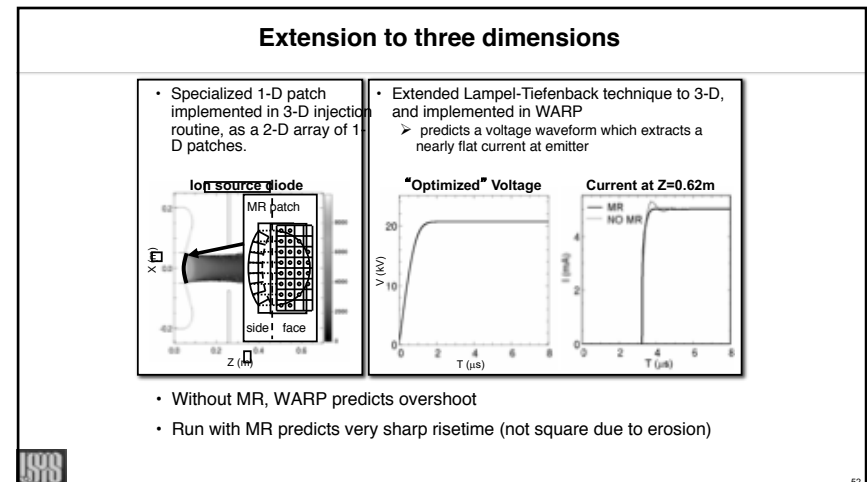
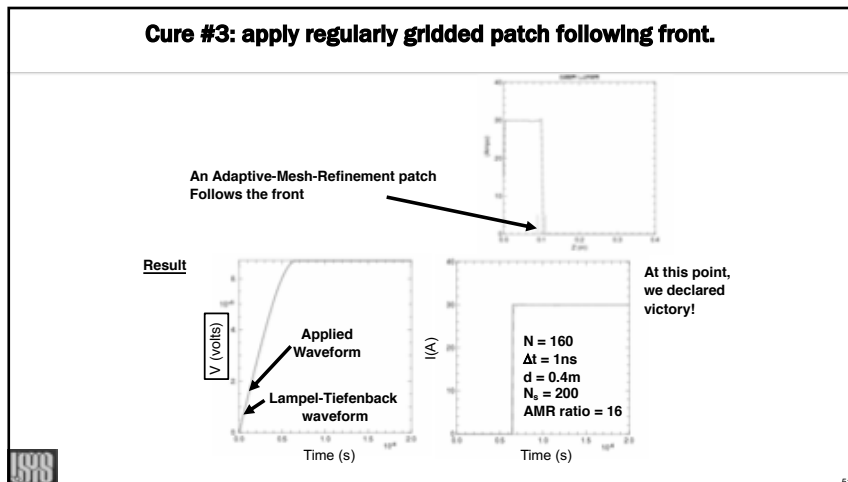
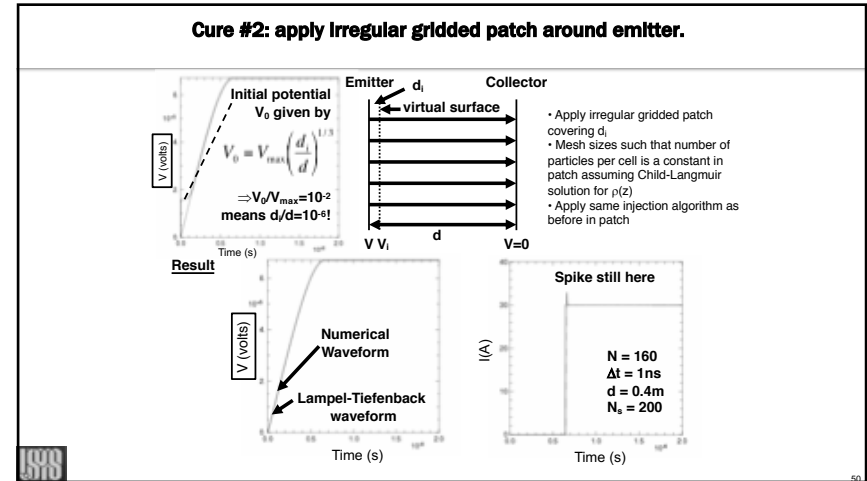
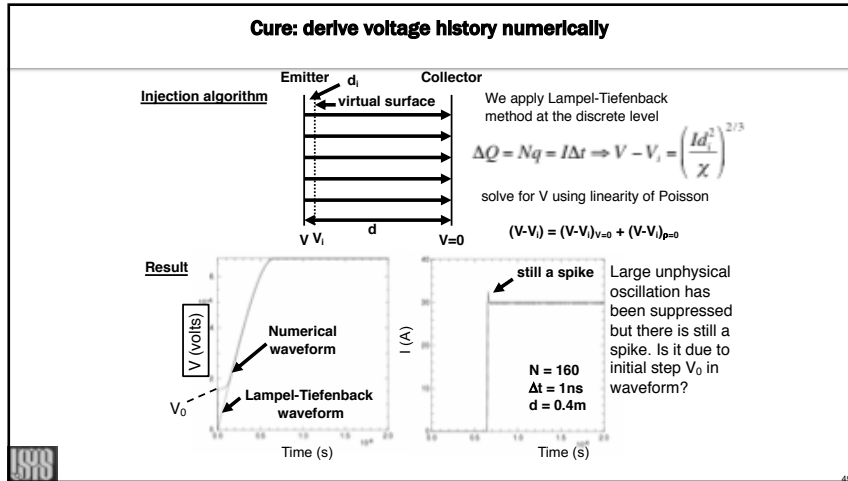
$$\frac{N}{\Delta t} = \chi \frac{(V - V_s)^{3/2}}{d_i^2} = C \cos$$

but the driving voltage is a continuous function derived analytically.

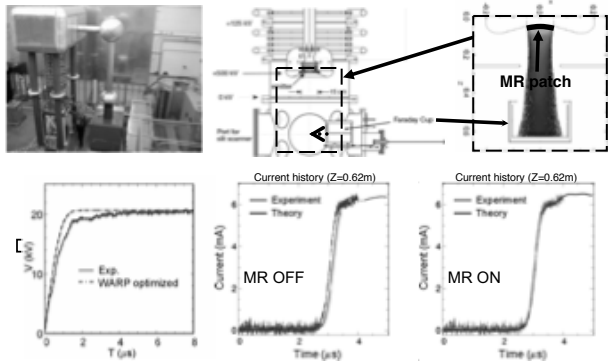
V (volts)

Time (s)

\Rightarrow Inconsistency due to infinitesimal solution applied in discrete world.

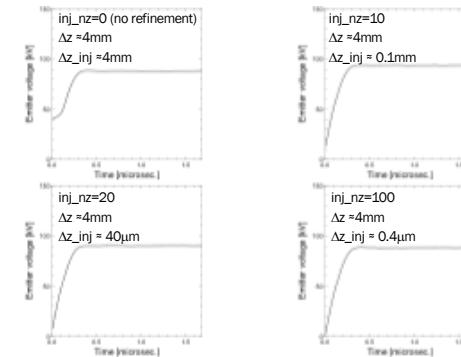


Test of MR patch on modeling of STS500 Experiment.



Pierce diode: exercise

- ① Open Pierce_diode_mrinj.py. Run with w3d.inj_nz = 0, 10, 20 and 100.
- ② Observe convergence of voltage at t=0 toward 0. Notice very small dz required!



AMR-PIC summary

- Mesh refinement (static or adaptive) can reduce simulation time by several.
- Care is needed to avoid spurious effects (spurious charge & reflections).
- Warp implementation has validated methods, but maintenance is lacking sufficient manpower:
 - ➔ To be used with great care by experience users.
 - ➔ Novel implementation with external AMR package (AMReX) is underway for AMR EM-PIC: WarpX.

References

1. J.-L. Vay, D. P. Grote, R. H. Cohen, & A. Friedman, "Novel methods in the Particle-In-Cell accelerator code-framework Warp", *Computational Science & Discovery* **5**, 014019 (2012)
2. Vay, J.-L.; Friedman, A.; Grote, D.P; "Application of Adaptive Mesh Refinement to PIC Simulations in Inertial Fusion", *Nuclear Inst. and Methods in Physics Research A* **544**, 347-352 (2005)
3. Vay J.-L., Colella P., Kwan JW., McCorquodale P., Serafini DB., Friedman A., Grote DP., Westenskow G., Adam JC., Heron A., Haber I., "Application of adaptive mesh refinement to particle-in-cell simulations of plasmas and beams" *Physics of Plasmas* **11**, 2928-2934 (2004)
4. Vay J.-L., Colella P, Friedman A, Grote DP, McCorquodale P, Serafini DB, "Implementations of mesh refinement schemes for particle-in-cell plasma simulations.", *Comput. Phys. Comm.* **164**, 297-305 (2004)
5. Vay J.-L., Adam JC, Héron A, "Asymmetric PML for the absorption of waves. Application to mesh refinement in electromagnetic particle-in-cell plasma simulations.", *Comput. Phys. Comm.* **164**, 171-177 (2004)